## Application/Control No. Applicant(s)/Patent Under Reexamination 10/046,859 **BOEHNKE ET AL. Notice of References Cited** Art Unit Examiner Page 1 of 1 Hien Tran 1764 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY 06-1991 Usui et al. 502/527.22 US-5,026,611 Α В US-С US-D US-E US-US-F US-G

## FOREIGN PATENT DOCUMENTS

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